

Notice of References Cited	Application/Control No. 10/541,815		Applicant(s)/Patent Under Reexamination GERLT ET AL.	
	Examiner Matthew W. Such		Art Unit 2891	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,447,879	09-2002	Sakurai et al.	428/161
*	B	US-6,958,270	10-2005	Misra et al.	438/257
*	C	US-6,908,536	06-2005	Beckmann, Udo	204/412
*	D	US-2004/0084080	05-2004	Sager et al.	136/263
*	E	US-2003/0087533	05-2003	Stupp et al.	438/745
*	F	US-5,942,388	08-1999	Willner et al.	435/6
*	G	US-7,074,519	07-2006	Kuhr et al.	429/149
*	H	US-6,300,141	10-2001	Segal et al.	435/287.1
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Roth, K.M., et al. "Characterization of Charge Storage in Redox-Active Self-Assembled Monolayers." LANGMUIR, Vol. 18 (2002): pp. 4030-4040.			
	V	Roth, K.M., et al. "Molecular Approaches Toward Information Storage Based on the Redox Properties of Porphyrins in Self-Assembled Monolayers." J. VAC. SCI. TECHNOL. B, Vol. 18, No. 5 (Sep/Oct 2000): pp. 2359-2364.			
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.